

Search Notes

Application/Control No.

10/655,942

Examiner

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Applicant(s)/Patent under
Reexamination

HASEGAWA, NAOYA

Art Unit

3729

SEARCHED

Class	Subclass	Date	Examiner
29	603.07 603.08 603.11- 603.16	2/22/2006	PK
	603.18		
360	324.11		
	324.12		
	324.2		
216	22,39 40		
427	127 128		
451	5, 41		
360	121 122		
	126 317		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PGPub text Search see attachment		10/11/2006	PK

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Reviewed Parent Application 09/905,330 (US PAT. 6,751,073)	2/22/2006	PK
Text Search EAT/NPL (IEEE)	2/23/2006	PK
Updated Text Search EAST		
Updated Text Search EAST/PGPub	10/11/2006	PK